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(54) **SPATIAL AND SPECTRAL WAVEFRONT ANALYSIS AND MEASUREMENT**

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(57) **ABSTRACT**

A method and apparatus for wavefront analysis including obtaining a plurality of differently phase changed transformed wavefronts corresponding to a wavefront being analyzed which has an amplitude and a phase, obtaining a plurality of intensity maps of the plurality of phase changed transformed wavefronts and employing the plurality of intensity maps to obtain an output indicating the amplitude and phase of the wavefront being analyzed.

